Se	earch	Notes	

Appli	cation/Control No.	Applicant(s)/Patent und Reexamination	der
10/53	6,752	IIMORI, YASUO	
Exam	iner	Art Unit	
Thail	Phan	2128	

SEARCHED			
Class	Subclass	Date	Examiner
703	2	5/17/2007	T.P.
703	7	5/17/2007	T.P.
700	146	5/17/2007	T.P.
700	182	5/17/2007	T.P.
702	42	5/17/2007	T.P.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		·)
	DATE	EXMR
USPTO patent database	5/17/2007	T.P
NPL on_line search: IEEE, ACM and commercial database	5/17/2007	T.P.
Bib. search	5/17/2007	T.P
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